

DMICA: exploring Dark Matter in natural muscovite MICA

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Pioneering DM search using muscovite mica by Snowden-Ifft et al. 1995

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Limits on Dark Matter Using Ancient Mica

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The combination of the track etching method and atomic force microscopy allows us to search for weakly interacting massive particles (WIMPs) in our Galaxy. A survey of 80720 μ m² of 0.5 Gyr old muscovite mica found no evidence of WIMP-recoil tracks. This enables us to set limits on WIMPs which are about an order of magnitude weaker than the best spin-dependent WIMP limits. Unlike other detectors, however, the mica method is, at present, not background limited. We argue that a background may not appear until we have pushed our current limits down by several orders of magnitude.

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FIG. 4. Exclusion curves for each of the main constituent nuclei of mica. For a given mass, WIMPs with cross sections above these curves are ruled out at the 90% confidence level.

- Snowden-Ifft et al. set one of the strictest limits on WIMPs cross section at that time, with an exposure of just 1e-6 tonne year.
- Following the methodology established by Snowden-Ifft et al., DMICA targets an exposure of 1 tonne year, equivalent to a scanning area of 800cm².

How mica works as detectors in the search for DM

Nuclear recoil events are recorded as "latent" tracks in mica

TRIM simulation of an oxygen ion (10 keV) traveling through mica



"Latent" tracks are series of atomic vacancies and invisible to microscopes.

Etching reveals latent tracks near cleavage in mica as pits



- Pits of several microns in size and nanometers in depth form at track sites.
- To effectively use mica as DM detector, the relationship between pit formation and recoil energy must be established.

Pit formation-recoil energy relation is examined through ion irradiation experiments varying ion species/energies



• Irradiating keV/u energy ions to simulate nuclear recoil in dark matter scattering

Larger stopping power results in higher pit formation efficiency



arXiv:2301.07118

Track etch model explaining pit formation efficiency (Snowden-Ifft and Chan 1995)



Probability of defect formation in a certain layer: $P(E; \mathbf{k}) = 1 - \exp(-\mathbf{k}S(E))$ \uparrow stopping power

Track etch model explaining pit formation efficiency (Snowden-Ifft and Chan 1995)



- Pit depth is the number of defects attacked by the etchant.
- The model predicts the observed pit depth histogram from the recoil energy spectrum.

alpha recoil tracks (ARTs), the most prevalent background



How to differentiate alpha recoil tracks



• Snowden-Ifft et al. (1995) found that paired-pits histogram shows zero for ARTs but a peak for neutron scattering tracks in the 40-64Aa bin.



Limits on dark matter from 80,720um² mica scan based on the null result in the smallest bins



FIG. 3. (a) The summed etched depths of tracks recorded in a 80720 μ m² scan of 0.5 Gyr old muscovite mica. No events appear between our cutoff of 40 and 64 Å (shown with a dashed vertical line). (b) The solid line shows the summed depths of etched neutron-recoil tracks. The dashed line shows the results of a MC program of these data. In both the real and MC data a large fraction of the events appear in the 40–64 Å gap.



FIG. 4. Exclusion curves for each of the main constituent nuclei of mica. For a given mass, WIMPs with cross sections above these curves are ruled out at the 90% confidence level.

Snowden-Ifft et al. 1995

Sensitivity projection for DMICA using paleoSpec/paleoSens

Pit depth histogram predicted using paleoSpec



Muscovite mica

 234Th recoiling tracks are not considered due to undetermined parameters in the etch model.

Exclusion curve derived for DMICA's target exposure of 1 ton yr



 High-mass end of the curve of DMICA could be significantly larger than that of the XENON1T experiment.

Impact of 234Th recoil on sensitivity projection



• For 234Th recoil, pit formation efficiency is assumed to be 100%.

High surface area-to-volume ratio in DMICA enables search for extremely heavy dark matter

• Number of DMs Passing through a Detector with Surface A during t > 1

$$Atv_{\chi}\left(\frac{\rho_{\chi}}{m_{\chi}}\right) > 1$$

• Upper Limit on Detectable DM Mass \propto Exposure $(Mt) \times$ Surface Area per Volume (A/V)

$$\begin{split} \text{XENON1T:} \quad & \left(\frac{m_{\chi}}{\text{GeV}}\right) < 10^{18} \left(\frac{Mt}{1\text{ton·yr}}\right) \left(\frac{A/V}{(1\text{m})^{-1}}\right) \\ \text{DMICA:} \quad & \left(\frac{m_{\chi}}{\text{GeV}}\right) < 10^{26} \left(\frac{Mt}{1\text{ton·yr}}\right) \left(\frac{A/V}{(10\text{nm})^{-1}}\right) \end{split}$$



How can we achieve the target exposure of 1 ton year?

Using AFM for mica scan restricts DM search throughput



- Generally, AFM involves a compromise between accuracy and scanning speed.
- Using optical profiler, through its non-contact measurement, significantly enhances mica scan throughput.

Pit measurement using an optical profiler



DMICA has tentatively processed mica of 524,765 um², 6.5x Snowden-Ifft et al.



Snowden-Ifft et al. 1995: 80,720 um^2 scan



FIG. 3. (a) The summed etched depths of tracks recorded in a 80720 μ m² scan of 0.5 Gyr old muscovite mica. No events appear between our cutoff of 40 and 64 Å (shown with a dashed vertical line). (b) The solid line shows the summed depths of etched neutron-recoil tracks. The dashed line shows the results of a MC program of these data. In both the real and MC data

Summary

- DMICA targets a 1-ton-year exposure in DM search in mica.
 - We employ the practical methodology established by Snowden-Ifft et al. (1995), substituting AFM with optical profiler for rapid mica scanning.
 - The projected sensitivity of DMICA assessed using paleoSens/paleoSpec is about 3 orders of magnitude worse than XENON1T.
 - Given our tentative processing of mica, 6.5 times greater than that achieved by Snowden-Ifft et al. (1995), we anticipate reaching the targeted exposure within a year.

Strategy to overcome alpha recoil backgrounds

- 8-chained tracks → make the gap in the smallest bins wider by increasing etch time
- 234Th single tracks → construct an appropriate track etch model by conducting irradiation experiments of heavy and energetic ions



Snowden-Ifft, Freeman, and Price Reply: The preceding Comment [1] by Collar brings up several interesting points which need to be considered when using ancient mica to set limits on dark matter [2]. The first considers a potential background from ²³⁴ Th recoiling from the first decay of ²³⁸U. Its range is similar to that of WIMP recoils, and a fraction $\sim T_{1/2}^{234}/T_{1/2}^{238} \approx 10^{-4.3}$ of ²³⁸U decays would stop at ²³⁴Th. We, however, observed no matched etched pits whose summed depth was larger than 64 Å. Furthermore, the requirement that each etch pit be at least 20 Å deep places a lower bound of 40 Å on the summed depth. Our limits resulted from no events having been observed in this gap. To estimate the background of recoiling ²³⁴ Th that fall in this gap one must use the correct etching model [3]. Collar uses a now discounted model. According to this new etching model [3] the observed density of etched pits in the gap resulting from these recoils is given by

 $\rho = N(\ln 2) \left(T^{234}_{1/2} / T^{238}_{1/2} \right) (P/2) \\ \times \left[(d/P)^2 - 4dt / P^2 + 4t^2 / P^2 \right],$

where *d* is the maximum summed depth in the gap, 64 Å, *P* is the range of the ²³⁴ Th recoil, 290 Å, and *t* is the threshold depth for an etched pit on one surface, 20 Å. We measured the uranium density for our mica to be $N = (1.7 \times 10^{-11}) (9 \times 10^{22}/\text{cm}^3) = 1.5 \times 10^{12} \text{ atoms/cm}^3$. Using these numbers we estimate a background from ²³⁴ Th at $\rho = 0.5/\text{cm}^2$. Since we have currently scanned only $8 \times 10^{-4} \text{ cm}^2$, we expect to be able to improve our limits by at least a factor of 2500 before running into this background. Further improvements are possible because

the spectrum of summed depths for these events differs markedly from that for WIMP recoils. As discussed in our paper, a much more serious threat comes from fast neutrons from U fission in the rock surrounding the mica. Finally, looking for tracks with etched depths greater than 500 Å, as suggested by Collar [4], is difficult because the flux distribution of WIMP's and the incoherence of the momentum transfer severely limit the number density of recoils which could produce such large etched pits.

We agree with Collar that the technique cannot be used to observe neutrinos from stellar collapse and support his suggestion that it could be used to place limits on clumps of dark matter.

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optical profiler (restored by deconvolution)



optical profiler resolution = 0.5um





AFM

AFM1

120

0 -

20 -

40 -

60 -

80 -

100 -

120 -

Ó

20

40

80

60

100

In microscopy, the PSF (Airy pattern) can be approximated with a Gaussian profile having a variance of (e.g., Zhang et al. 2007)

$$\sigma \approx 0.22 \left(\frac{\lambda}{\mathrm{NA}}\right) = 0.22 \text{ um} = 1.27 \text{ pixel},$$

where NA = 0.55 and $\lambda = 0.55$ um are applied.



ピットの個数・深さを読み出すために白色干渉計を用いる



劈開面から10nm程度の深さまでに存在 したトラックがピットとして現れている



DMICAでは800cm²の劈開面測定を目指す

- 1視野(3e-4cm²)の測定に5秒かかる
- 1試料(2cm²)の測定が1日(9.2時間)で完了する
- のべ400日でのべ800cm²の測定を達成

JAMSTEC will host the next MDvDM meeting in Yokohama, Japan tentative schedule: May 20-23, 2025

